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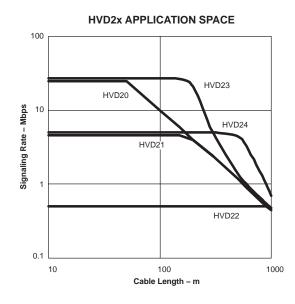
EXTENDED COMMON-MODE RS-485 TRANSCEIVERS

FEATURES

- Common-Mode Voltage Range (–20 V to 25 V) More Than Doubles TIA/EIA-485 Requirement
- Receiver Equalization Extends Cable Length, Signaling Rate (HVD23, HVD24)
- Reduced Unit-Load for up to 256 Nodes
- Bus I/O Protection to Over 16-kV HBM
- Failsafe Receiver for Open-Circuit, Short-Circuit and Idle-Bus Conditions
- Low Standby Supply Current 1-μA Max
- More Than 100 mV Receiver Hysteresis

APPLICATIONS

- Long Cable Solutions
 - Factory Automation
 - Security Networks
 - Building HVAC
- Severe Electrical Environments
 - Electrical Power Inverters
 - Industrial Drives
 - Avionics



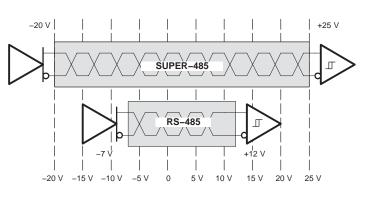
DESCRIPTION

The transceivers in the HVD2x family offer performance far exceeding typical RS-485 devices. In addition to meeting all requirements of the TIA/EIA-485-A standard, the HVD2x family operates over an extended range of common-mode voltage, and has features such as high ESD protection, wide receiver hysteresis, and failsafe operation. This family of devices is ideally suited for long-cable networks, and other applications where the environment is too harsh for ordinary transceivers.

These devices are designed for bidirectional data transmission on multipoint twisted-pair cables. Example applications are digital motor controllers, remote sensors and terminals, industrial process control, security stations, and environmental control systems.

These devices combine a 3-state differential driver and a differential receiver, which operate from a single 5-V power supply. The driver differential outputs and the receiver differential inputs are connected internally to form a differential bus port that offers minimum loading to the bus. This port features an extended common-mode voltage range making the device suitable for multipoint applications over long cable runs.

HVD2x Devices Operate Over a Wider Common-Mode Voltage Range



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



SLLS552C - DECEMBER 2002 - REVISED SEPTEMBER 2003



These devices have limited built-in ESD protection. The leads should be shorted together or the device placed in conductive foam during storage or handling to prevent electrostatic damage to the MOS gates.

DESCRIPTION (continued)

The 'HVD20 provides high signaling rate (up to 25 Mbps) for interconnecting networks of up to 64 nodes.

The 'HVD21 allows up to 256 connected nodes at moderate data rates (up to 5 Mbps). The driver output slew rate is controlled to provide reliable switching with shaped transitions which reduce high-frequency noise emissions.

The 'HVD22 has controlled driver output slew rate for low radiated noise in emission-sensitive applications and for improved signal quality with long stubs. Up to 256 'HVD22 nodes can be connected at signaling rates up to 500 kbps.

The 'HVD23 implements receiver equalization technology for improved jitter performance on differential bus applications with data rates up to 25 Mbps at cable lengths up to 160 meters.

The 'HVD24 implements receiver equalization technology for improved jitter performance on differential bus applications with data rates in the range of 1 Mbps to 10 Mbps at cable lengths up to 1000 meters.

The receivers also include a failsafe circuit that provides a high-level output within 250 microseconds after loss of the input signal. The most common causes of signal loss are disconnected cables, shorted lines, or the absence of any active transmitters on the bus. This feature prevents noise from being received as valid data under these fault conditions. This feature may also be used for Wired-Or bus signaling.

The SN65HVD2X devices are characterized for operation over the temperature range of -40°C to 85°C.

PART NUMBERS	CABLE LENGTH AND SIGNALING RATE ⁽¹⁾	NODES	MARKING
SN65HVD20	Up to 50 m at 25 Mbps	Up to 64	D: VP20 P: 65HVD20
SN65HVD21	Up to 150 m at 5 Mbps (with slew rate limit)	Up to 256	D: VP21 P: 65HVD21
SN65HVD22	Up to1200 m at 500 kbps (with slew rate limit)	Up to 256	D: VP22 P: 65HVD22
SN65HVD23	Up to 160 m at 25 Mbps (with receiver equalization)	Up to 64	D: VP23 P: 65HVD23
SN65HVD24	Up to 500 m at 3 Mbps (with receiver equalization)	Up to 256	D: VP24 P: 65HVD24

PRODUCT SELECTION GUIDE

(1) Distance and signaling rate predictions based upon Belden 3105A cable and 15% eye pattern jitter.

AVAILABLE OPTIONS

PLASTIC THROUGH-HOLE P-PACKAGE (JEDEC MS-001)	PLASTIC SMALL-OUTLINE ⁽¹⁾ D-PACKAGE (JEDEC MS-012)
SN65HVD20P	SN65HVD20D
SN65HVD21P	SN65HVD21D
SN65HVD22P	SN65HVD22D
SN65HVD23P	SN65HVD23D
SN65HVD24P	SN65HVD24D

(1) Add R suffix for taped and reeled carriers.

SLLS552C - DECEMBER 2002 - REVISED SEPTEMBER 2003

н	HVD20, HVD21, HVD22				HVD23, HVD2	24	
INPUT	ENABLE	OUT	PUTS	INPUT	ENABLE	OUTF	PUTS
D	DE	Α	В	D	DE	Α	В
Н	Н	Н	L	Н	Н	Н	L
L	н	L	Н	L	н	L	Н
Х	L	Z	Z	х	L	Z	Z
Х	OPEN	Z	Z	х	OPEN	Z	Z
OPEN	Н	Н	L	OPEN	Н	L	Н

DRIVER FUNCTION TABLE

H = high level, L= low level, X = don't care, Z = high impedance (off), ? = indeterminate

RECEIVER FUNCTION TABLE

DIFFERENTIAL INPUT	ENABLE	OUTPUT
$V_{ID} = (V_A - V_B)$	RE	R
$0.2 \text{ V} \leq \text{V}_{ID}$	L	Н
$-0.2 \text{ V} < \text{V}_{\text{ID}} < 0.2 \text{ V}$	L	H (see Note A)
$V_{ID} \le -0.2 V$	L	L
Х	н	Z
Х	OPEN	Z
Open circuit	L	Н
Short Circuit	L	Н
Idle (terminated) bus	L	Н

H = high level, L= low level, Z = high impedance (off)

NOTE A: If the differential input V_{ID} remains within the transition range for more than 250 μ s, the integrated failsafe circuitry detects a bus fault, and set the receiver output to a high state. See Figure 15.

ABSOLUTE MAXIMUM RATINGS (1)

			SN65HVD2X	
Supply voltage(2), V _{CC}			–0.5 V to 7 V	
Voltage at any bus I/O terminal			–27 V to 27 V	
Voltage input, transient put	-60 V to 60 V			
Voltage input at any D, DE	or RE terminal		–0.5 V to V _{CC} + 0.5 V	
	Likuman Dadu Madal(3)	A, B, GND	16 kV	
Electro static dis de succ	Human Body Model ⁽³⁾	All pins	5 kV	
Electrostatic discharge	Charged-Device Model ⁽⁴⁾	All pins	1.5 kV	
	Machine Model ⁽⁵⁾	All pins	200 V	
Continuous total power dis	sipation	·	See Power Dissipation Rating Table	
Junction temperature, TJ		150°C		
Storage temperature, T _{Stg}	Storage temperature, T _{Stg}			

(1) Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

(2) All voltage values, except differential I/O bus voltages, are with respect to network ground terminal.

(3) Tested in accordance with JEDEC Standard 22, Test Method A114-A.

(4) Tested in accordance with JEDEC Standard 22, Test Method C101.

(5) Tested in accordance with JEDEC Standard 22, Test Method A115-A.

SLLS552C - DECEMBER 2002 - REVISED SEPTEMBER 2003



POWER DISSIPATION RATINGS

PACKAGE	CIRCUIT BOARD MODEL	T _A ≤ 25°C POWER RATING	DERATING FACTOR(3) ABOVE T _A = 25°C	T _A = 70°C POWER RATING	T _A = 85°C POWER RATING
	Low-K(1)	577 mW	4.62 mW/°C	369 mW	300 mW
D	High-K(2)	913 mW	7.3 mW/°C	584 mW	474 mW
	Low-K(1)	984 mW	7.87 mW/°C	630 mW	512 mW
Р	High-K ⁽²⁾	1344 mW	10.8 mW/°C	860 mW	700 mW

(1) In accordance with the Low-K thermal metric definitions of EIA/JESD51-3.

(2) In accordance with the High-K thermal metric definitions of EIA/JESD51–7.
(3) This is the inverse of the junction-to-ambient thermal resistance when board-mounted and with no air flow.

THERMAL CHARACTERISTICS

	PARAMETER			TEST CONDITIONS		VALUE	UNITS
	has a fact to the and the second second	·	D			86.2	
θJB	θ _{JB} Junction-to-board thermal resistance		Р			56	0000
	0		D			47.1	°C/W
θJC	Junction-to-case thermal resis	stance	Р			54	
		HVD20	$V_{CC} = 5 V, T_{J} = 25^{\circ}C,$	25 Mbps	295		
			HVD21	$ \begin{array}{ll} R_L = 54 \ \Omega, \ C_L = 50 \ pF \ (driver), \\ C_L = 15 \ pF \ (receiver), \\ 50\% \ Duty \ cycle \ square-wave \ signal, \\ Driver \ and \ receiver \ enabled \\ \end{array} $	5 Mbps	260	
		Typical	HVD22		50% Duty cycle square-wave signal,	233	
			HVD23			25 Mbps	302
_	D		HVD24		5 Mbps	267	
PD	Device power dissipation		HVD20		25 Mbps	408	mW
			HVD21	$_2$ C _L = 50 pF, C _L = 15 pF (receiver), 500 kbps	5 Mbps	342	
		Worst case	HVD22		500 kbps	300	
			HVD23	50% Duty cycle square-wave signal, Driver and receiver enabled	25 Mbps	417	
		HVD24			5 Mbps	352	
T _{SD}	Thermal shut-down junction te	emperature	•		•	170	°C

RECOMMENDED OPERATING CONDITIONS

		MIN	NOM	MAX	UNIT
Supply voltage, V _{CC}		4.5	5	5.5	V
Voltage at any bus I/O terminal	A, B	-20		25	V
High-level input voltage, VIH		2		VCC	
Low-level input voltage, VIL	D, DE, RE	0	0.8		V
Differential input voltage, VID	A with respect to B	-25		25	V
Output summal	Driver	-110		110	
Output current	Receiver	-8		8	mA
Operating free-air temperature, TA	(1)	-40		85	°C
Junction temperature, TJ		-40		130	°C

(1) Maximum free-air temperature operation is allowed as long as the device recommended junction temperature is not exceeded.



SLLS552C - DECEMBER 2002 - REVISED SEPTEMBER 2003

DRIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)(1)

PARAMETER		PARAMETER TEST CONDITIONS		MIN	TYP(1)	MAX	UNIT
VIK	Input clamp voltage	Ij = -18 mA		-1.5	0.75		V
VO	Open-circuit output voltage	A or B, No load		0		VCC	V
		No load (open circuit)		3.3	4.2	VCC	
VOD(SS)	Steady-state differential output voltage magnitude	R _L = 54 Ω,	See Figure 1	1.8	2.5		V
02(00)	magnitude	With common-mode loading	ig, See Figure 2	1.8			
$\Delta VOD(SS) $	Change in steady-state differential output voltage between logic states	See Figure 1 and Figure 3		-0.1		0.1	V
VOC(SS)	Steady-state common-mode output voltage	See Figure 1		2.1	2.5	2.9	V
$\Delta VOC(SS)$	Change in steady-state common-mode output voltage, VOC(H) – VOC(L)	See Figure 1 and Figure 4		-0.1		0.1	V
VOC(PP)	Peak-to-peak common-mode output voltage, VOC(MAX) - VOC(MIN)	$R_L = 54 \Omega$, $C_L = 50 pF$, See Figure 1 and Figure 4			0.35		V
VOD(RING)	Differential output voltage over and under shoot	$R_L = 54 \Omega$, $C_L = 50 pF$, S	See Figure 5			10%	
lı (Input current	D, DE		-100		100	μΑ
IO(OFF)	Output current with power off	$V_{CC} < = 2.5 V$		See re	ceiver line	input	
loz	High impedance state output current	DE at 0 V		1	current		
los	Short-circuit output current	$V_{O} = -20$ V to 25 V,	See Figure 9	-250		250	mA
COD	Differential output capacitance			See receiver C			

(1) All typical values are at V_{CC} = 5 V and 25°C.

DRIVER SWITCHING CHARACTERISTICS

over recommended operating conditions (unless otherwise noted)

	PARAMETER	TEST C	ONDITIONS	MIN	TYP(1)	MAX	UNIT	
tPLH	Differential output propagation delay, low-to- high	R _I = 54 Ω,	HVD20, HVD23	6	10	20		
"F LI I		$C_{L}^{-} = 50 \text{ pF},$	HVD21, HVD24	20	32	60	ns	
^t PHL	Differential output propagation delay, high-to-low	See Figure 3	HVD22	160	280	500		
tr	Differential output rise time	R _I = 54 Ω,	HVD20, HVD23	2	6	12		
4		$C_{L} = 50 \text{ pF},$	HVD21, HVD24	20	40	60	ns	
tf	Differential output fall time	See Figure 3	HVD22	200	400	600		
^t PZH	Propagation delay time, high-impedance-to-high-level output		HVD20, HVD23			40		
ΨΖΠ		RE at 0 V, See Figure 6	HVD21, HVD24			100	ns	
^t PHZ	Propagation delay time, high-level-output-to-high-impedance	See rigule o	HVD22			300		
tPZL	Propagation delay time, high-impedance-to-low-level output		HVD20, HVD23			40		
ΥZL		RE at 0 V, See Figure 7	HVD21, HVD24			100	ns	
^t PLZ	Propagation delay time, low-level-output-to-high-impedance	See Figure /	HVD22			300		
^t d(standby)	Time from an active differential output to standby		Saa Firuna O			2	μs	
td(wake)	Wake-up time from standby to an active differential output	RE at V _{CC} , S	see Figure 8			8	μs	
		HVD20, HVD2	23			2		
^t sk(p)	Pulse skew tpLH - tpHL	HVD21, HVD24				6	ns	
		HVD22				50		

(1) All typical values are at $V_{CC} = 5 V$ and $25^{\circ}C$.

SLLS552C - DECEMBER 2002 - REVISED SEPTEMBER 2003

RECEIVER ELECTRICAL CHARACTERISTICS

over recommended operating conditions

PARAMETER		TEST	MIN	түр(1)	MAX	UNIT	
V _{IT(+)}	Positive-going differential input voltage threshold	See Figure 10	$V_{O} = 2.4 \text{ V}, I_{O} = -8 \text{ mA}$		60	200	
VIT(-)	Negative-going differential input voltage threshold	See Figure 10	$V_{O} = 0.4 \text{ V}, I_{O} = 8 \text{ mA}$	-200	-60		mV
VHYS	Hysteresis voltage (V _{IT+} – V _{IT} _)			100	130		mV
V	Positive-going differential input failsafe voltage	See Figure 15	$V_{CM} = -7 V$ to 12 V	40	120	200	mV
V _{IT(F+)}	threshold	See Figure 15	V_{CM} = -20 V to 25 V		120	250	IIIV
	Negative-going differential input failsafe voltage	See Figure 15	$V_{CM} = -7 V$ to 12 V	-200	-120	-40	mV
V _{IT(F–)}	threshold	See Figure 15	V_{CM} = -20 V to 25 V	-250	-120		ΠIV
VIK	Input clamp voltage	II = -18 mA		-1.5			V
VOH	High-level output voltage	$V_{ID} = 200 \text{ mV}, I_{OH}$	$V_{ID} = 200 \text{ mV}, I_{OH} = -8 \text{ mA}, \text{ See Figure 11}$				V
VOL	Low-level output voltage	$V_{ID} = -200 \text{ mV}, I_{O}$	L = 8 mA, See Figure 11			0.4	V
		$V_{I} = -7$ to 12 V,	HVD20, HVD23	-400		500	
lunua	Pup input ourrest (nower on or newer off)	Other input = 0 V	HVD21, HVD22, HVD24	-100		125	– uA
li(BUS)	Bus input current (power on or power off)	$V_{I} = -20$ to 25 V,	HVD20, HVD23	-800		1000	
		Other input = 0 V	HVD21, HVD22, HVD24	-200		250	
lj	Input current	RE		-100		100	μΑ
D.		HVD20, 23		24			ko
Rj	Input resistance	HVD21, 22, 24		96			kΩ
CID	Differential input capacitance	V _{ID} = 0.5 + 0.4 sin	e (2π x 1.5 x 10 ⁶ t)			20	pF

(1) All typical values are at 25°C.

RECEIVER SWITCHING CHARACTERISTICS

over recommended operating conditions

	PARAMETER	TEST	CONDITIONS	MIN	TYP	MAX	UNIT
^t PLH	Propagation delay time, low-to-high level output	Coo Eiruno 44	HVD20, HVD23		16	35	
^t PHL	Propagation delay time, high-to-low level output	See Figure 11	HVD21, HVD22, HVD24		25	50	ns
t _r	Receiver output rise time	See Figure 11			0	4	
t _f	Receiver output fall time	See Figure 11			2	4	ns
^t PZH	Receiver output enable time to high level	Soo Figuro 12		90	120	-	
^t PHZ	Receiver output disable time from high level	See Figure 12		16	35	ns	
t _{PZL}	Receiver output enable time to low level	See Figure 12		90	120	~~	
^t PLZ	Receiver output disable time from low level	See Figure 13			16	35	ns
^t r(standby)	Time from an active receiver output to standby					2	
^t r(wake)	Wake-up time from standby to an active receiver output	See Figure 14,	See Figure 14, DE at 0 V			8	μs
^t sk(p)	Pulse skew tpLH - tpHL					5	ns
^t p(set)	Delay time, bus fail to failsafe set	See Figure 15. pulse rate = 1 kHz			250	350	μs
tp(reset)	Delay time, bus recovery to failsafe reset	See Figure 15,				50	ns





SLLS552C - DECEMBER 2002 - REVISED SEPTEMBER 2003

RECEIVER EQUALIZATION CHARACTERISTICS(1)

over recommended operating conditions

PARAMETER		TEST CON	MIN TYP(2)	MAX	UNIT			
	Peak-to-peak eye-patttern jitter	Pseudo-random NRZ code with a bit pattern length of 2 ¹⁶ – 1 , Beldon 3105A cable, See Figure 27		0 m	HVD23	2		-
			25 Mbps	100 m	HVD20	6		
				100 m	HVD23	3		
				150 m	HVD20	15		
				130 111	HVD23	4		
				200 m	HVD20	27		
				200 111	HVD23	8		
			10 Mbps	200 m	HVD20	22		
^t j(pp)				200 111	HVD23	8		
				250 m	HVD20	34		
				250 111	HVD23	15	-	ns
				300 m	HVD20	49		
				300 111	HVD23	27		
			5 Mbps	500 m	HVD21	128		
				500 m	HVD24	18		
			3 Mbps		HVD20	93		
				500 m	HVD21	103		
				500 111	HVD23 90			
					HVD24	16		
			1 Mbpc	1000 m	HVD21	216		
			1 Mbps	1000 111	HVD24	62		

(1) The HVD20 and HVD21 do not have receiver equalization, but are specified for comparison.

(2) All typical values are at $V_{CC} = 5$ V, and temperature = 25° C.

SUPPLY CURRENT

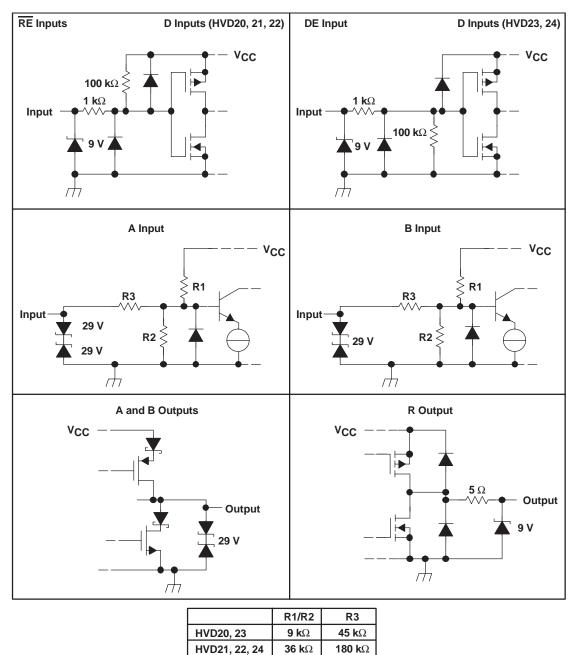
over recommended operating conditions (unless otherwise noted)

PARAMETER		TEST CONDITIONS			TYP	MAX	UNIT
	Supply current	Driver enabled (DE at V _{CC}), Receiver enabled (RE at 0 V) No load, $V_I = 0$ V or V _{CC}	HVD20		6	9	
			HVD21		8	12	
			HVD22		6	9	mA
			HVD23		7	11	
			HVD24		10	14	
		Driver enabled (DE at V _{CC}), Receiver disabled (RE at V _{CC}) No load, $V_I = 0$ V or V _{CC}	HVD20		5	8	
			HVD21		7	11	mA
			HVD22		5	8	
ICC			HVD23		5	9	
			HVD24		8	12	
		Driver disabled (DE at 0 V), Receiver enabled (RE at 0 V) No load	HVD20		4	7	
			HVD21		5	8	
			HVD22		4	7	mA
			HVD23		4.5	9	
			HVD24		5.5	10	
		Driver disabled (DE at 0 V), Receiver disabled (RE at $V_{\mbox{CC}})$ D open	All HVD2x			1	μΑ

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EQUIVALENT INPUT AND OUTPUT SCHEMATIC DIAGRAMS





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TEXAS IRUMENTS

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NOTES:

Test load capacitance includes probe and jig capacitance (unless otherwise specified). Signal generator characteristics: rise and fall time < 6 ns, pulse rate 100 kHz, 50% duty cycle, $Z_0 = 50 \Omega$ (unless otherwise specified)

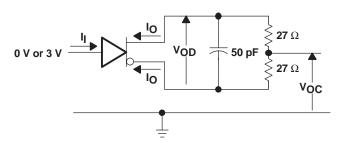


Figure 1. Driver Test Circuit, V_{OD} and V_{OC} Without Common-Mode Loading

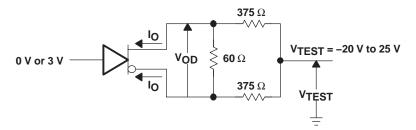


Figure 2. Driver Test Circuit, V_{OD} With Common-Mode Loading

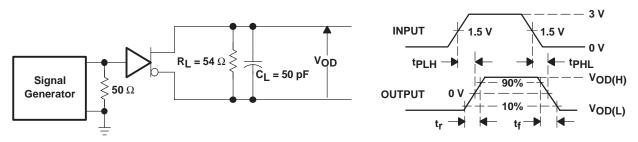


Figure 3. Driver Switching Test Circuit and Waveforms

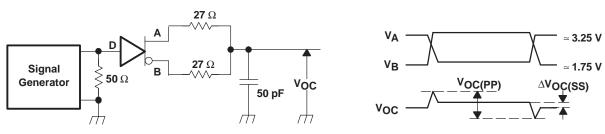
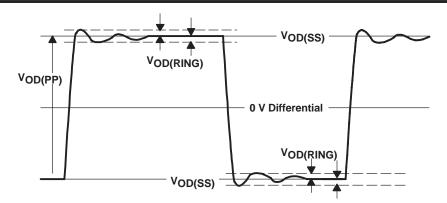


Figure 4. Driver V_{OC} Test Circuit and Waveforms

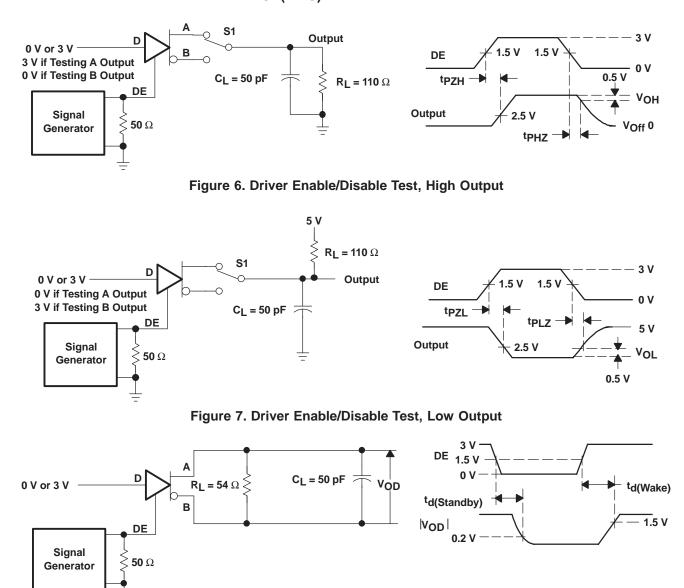
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NOTE: V_{OD}(RING) is measured at four points on the output waveform, corresponding to overshoot and undershoot from the V_{OD}(H) and V_{OD}(L) steady state values.

Figure 5. VOD(RING) Waveform and Definitions







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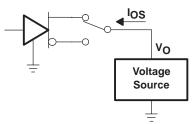


Figure 9. Driver Short-Circuit Test

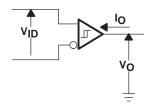


Figure 10. Receiver DC Parameter Definitions

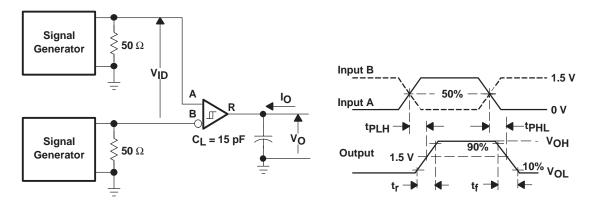
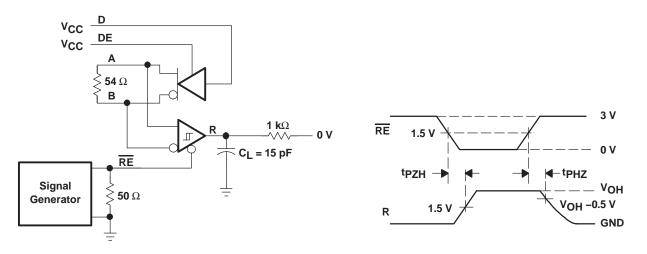
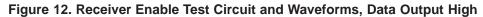
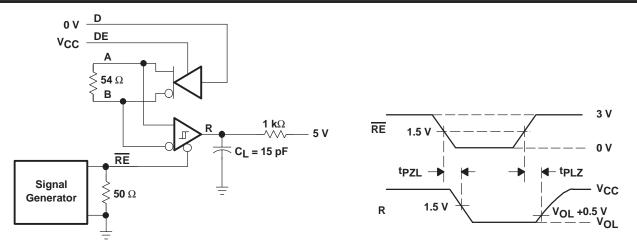


Figure 11. Receiver Switching Test Circuit and Waveforms





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IEXAS TRUMENTS

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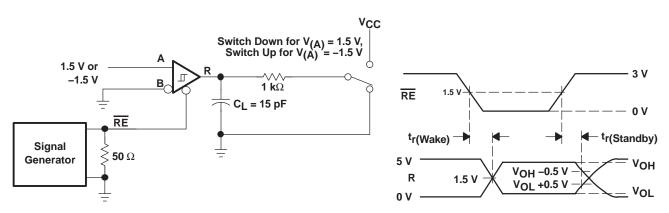
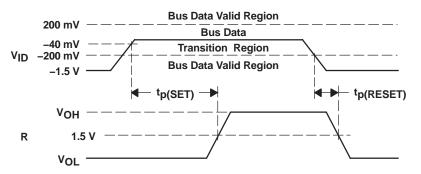
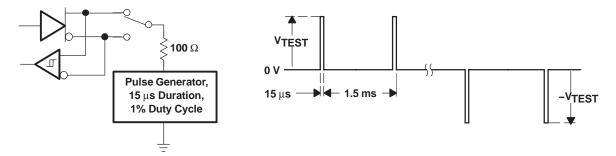


Figure 14. Receiver Standby and Wake Test Circuit and Waveforms





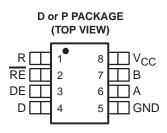




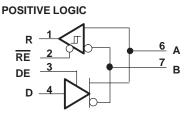


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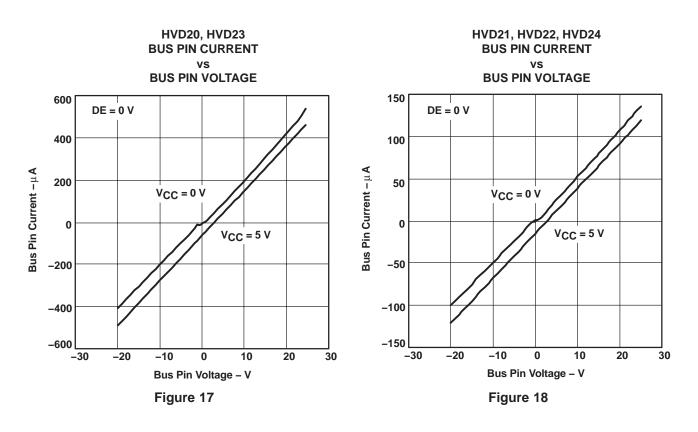
PIN ASSIGNMENTS



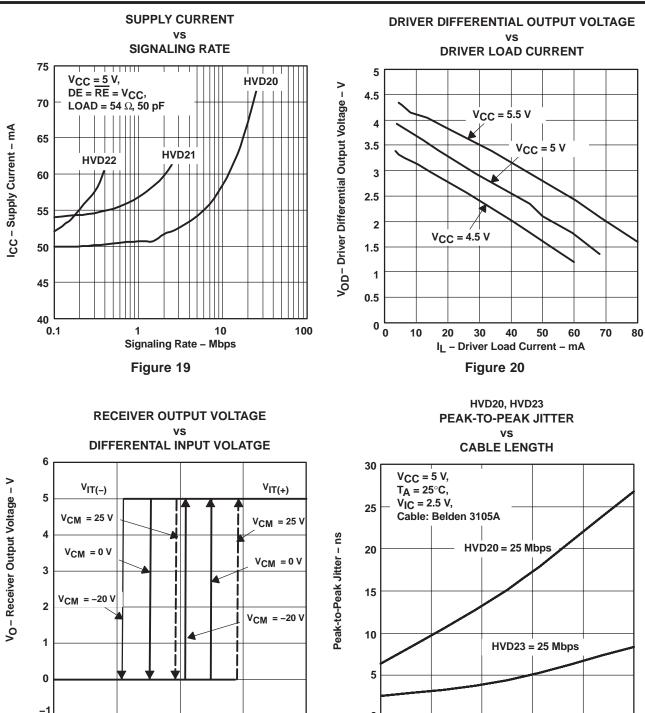
LOGIC DIAGRAM



TYPICAL CHARACTERISTICS



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0

100

120



-0.1

0

VID - Differential Input Voltage - V

0.1

0.2



Cable Length – m

160

180

200

140

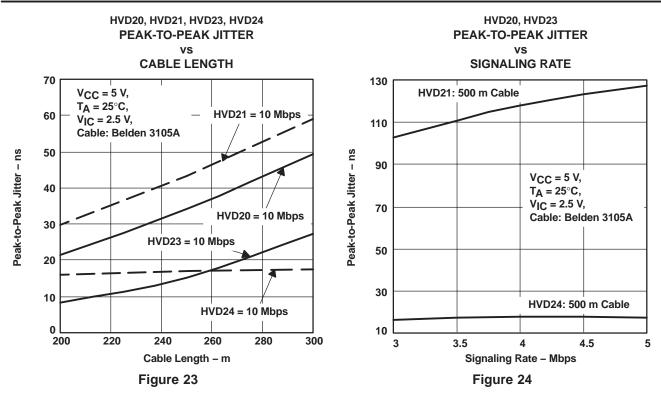
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-0.2



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APPLICATION INFORMATION

THEORY OF OPERATION

The HVD2x family of devices integrates a differential receiver and differential driver with additional features for improved performance in electrically-noisy, long-cable, or other fault-intolerant applications.

The receiver hysteresis (typically 130 mV) is much larger than found in typical RS-485 transceivers. This helps reject spurious noise signals which would otherwise cause false changes in the receiver output state.

Slew rate limiting on the driver outputs (SN65HVD21, 22, and 24) reduces the high-frequency content of signal edges. This decreases reflections from bus discontinuities, and allows longer stub lengths between nodes and the main bus line. Designers should consider the maximum signaling rate and cable length required for a specific application, and choose the transceiver best matching those requirements.

When DE is low, the differential driver is disabled, and the A and B outputs are in high-impedance states. When DE is high, the differential driver is enabled, and drives the A and B outputs according to the state of the D input.

When \overline{RE} is high, the differential receiver output buffer is disabled, and the R output is in a high-impedance state. When \overline{RE} is low, the differential receiver is enabled, and the R output reflects the state of the differential bus inputs on the A and B pins.

If both the driver and receiver are disabled, (DE low and \overline{RE} high) then all nonessential circuitry, including auxiliary functions such as failsafe and receiver equalization is placed in a low-power standby state. This reduces power consumption to less than 5 μ W. When either enable input is asserted, the circuitry again becomes active.

In addition to the primary differential receiver, these devices incorporate a set of comparators and logic to implement an active receiver failsafe feature. These components determine whether the differential bus signal is valid. Whenever the differential signal is close to zero volts (neither high nor low), a timer initiates, If the differential input remains within the transition range for more than 250 microseconds, the timer expires and set the receiver output to the high state. If a valid bus input (high or low) is received at any time, the receiver output reflects the valid bus state, and the timer is reset.

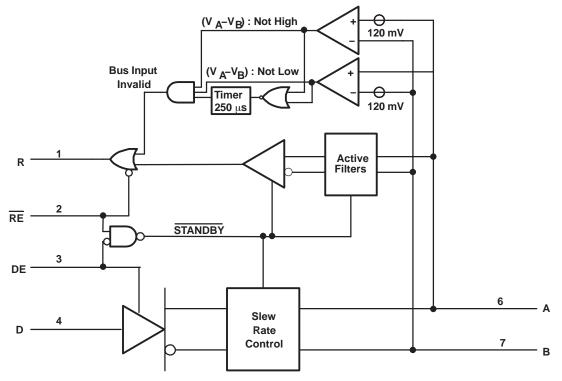


Figure 25. Function Block Diagram



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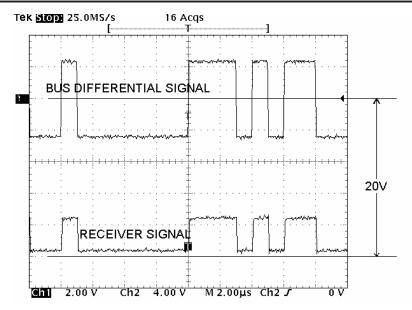


Figure 26. HVD22 Receiver Operation With 20-V Offset on Input Signal

$ \begin{array}{ c c c c c c c c } \hline H(s) &=& k_0 \Bigg[\left(1-k_1\right) + \frac{k_1 p_1}{\left(s+p_1\right)} \Bigg] \Bigg[\left(1-k_2\right) + \frac{k_2 p_2}{\left(s+p_2\right)} \Bigg] \Bigg[\left(1-k_3\right) + \frac{k_3 p_3}{\left(s+p_3\right)} \Bigg] \end{array} \end{array} $	k0 (DC loss)	p1 (MHz)	k1	p2 (MHz)	k2	p3 (MHz)	k3
Similar to 160m of Belden 3105A	0.95	0.25	0.3	3.5	0.5	15	1
Similar to 250m of Belden 3105A	0.9	0.25	0.4	3.5	0.7	12	1
Similar to 500m of Belden 3105A	0.8	0.25	0.6	2.2	1	8	1
Similar to 1000m of Belden 3105A	0.6	0.3	1	3	1	6	1



Figure 27. Cable Attenuation Model for Jitter Measurements



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INTEGRATED RECEIVER EQUALIZATION USING THE HVD23

Figure 28 illustrates the benefits of integrated receiver equalization as implemented in the HVD23 transceiver. In this test setup, a differential signal generator applied a signal voltage at one end of the cable, which was Belden 3105A twisted-pair shielded cable. The test signal was a pseudo-random bit stream (PRBS) of nonreturn-to-zero (NRZ) data. Channel 1 (top) shows the eye-pattern of the differential voltage at the receiver inputs (after the cable attenuation). Channel 2 (bottom) shows the output of the receiver.



Figure 28. HVD23 Receiver Performance at 25 Mbps Over 150 Meter Cable



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INTEGRATED RECEIVER EQUALIZATION USING THE HVD24

Figure 29 illustrates the benefits of integrated receiver equalization as implemented in the HVD24 transceiver. In this test setup, a differential signal generator applied a signal voltage at one end of the cable, which was Belden 3105A twisted-pair shielded cable. The test signal was a pseudo-random bit stream (PRBS) of nonreturn-to-zero (NRZ) data. Channel 1 (top) shows the eye-pattern of the bit stream. Channel 2 (middle) shows the eye-pattern of the differential voltage at the receiver inputs (after the cable attenuation). Channel 3 (bottom) shows the output of the receiver.

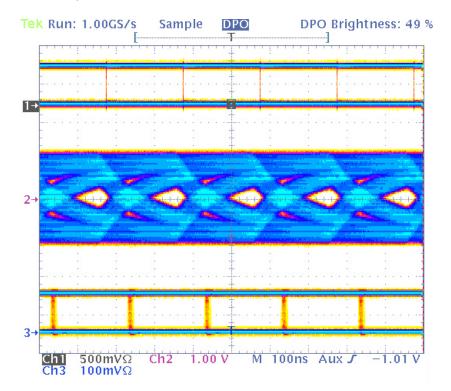


Figure 29. HVD24 Receiver Performance at 5 Mbps Over 500 Meter Cable



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NOISE CONSIDERATIONS FOR EQUALIZED RECEIVERS

The simplest way of overcoming the effects of cable losses is to increase the sensitivity of the receiver. If the maximum attenuation of frequencies of interest is 20 dB, increasing the receiver gain by a factor of ten compensates for the cable. However, this means that both signal and noise are amplified. Therefore, the receiver with higher gain is more sensitive to noise and it is important to minimize differential noise coupling to the equalized receiver.

Differential noise is crated when conducted or radiated noise energy generates more voltage on one line of the differential pair than the other. For this to occur from conducted or electric far-field noise, the impedance to ground of the lines must differ.

For noise frequency out to 50 MHz, the input traces can be treated as a lumped capacitance if the receiver is approximately 10 inches or less from the connector. Therefore, matching impedance of the lines is accomplished by matching the lumped capacitance of each.

The primary factors that affect the capacitance of a trace are in length, thickness, width, dielectric material, distance from the signal return path, stray capacitance, and proximity to other conductors. It is difficult to match each of the variables for each line of the differential pair exactly, but a reasonable effort to do so keeps the lines balanced and less susceptible to differential noise coupling.

Another source of differential noise is from near-field coupling. In this situation, an assumption of equal noise-source impedance cannot be made as in the far-field. Familiarly known as crosstalk, more energy from a nearby signal is coupled to one line of the differential pair. Minimization of this differential noise is accomplished by keeping the signal pair close together and physical separation from high-voltage, high-current, or high-frequency signals.

In summary, follow these guidelines in board layout for keeping differential noise to a minimum.

- Keep the differential input traces short.
- Match the length, physical dimensions, and routing of each line of the pair.
- Keep the lines close together.
- Match components connected to each line.
- Separate the inputs from high-voltage, high-frequency, or high-current signals.

MECHANICAL DATA

MPDI001A - JANUARY 1995 - REVISED JUNE 1999



- NOTES: A. All linear dimensions are in inches (millimeters).
 - B. This drawing is subject to change without notice.
 - C. Falls within JEDEC MS-001

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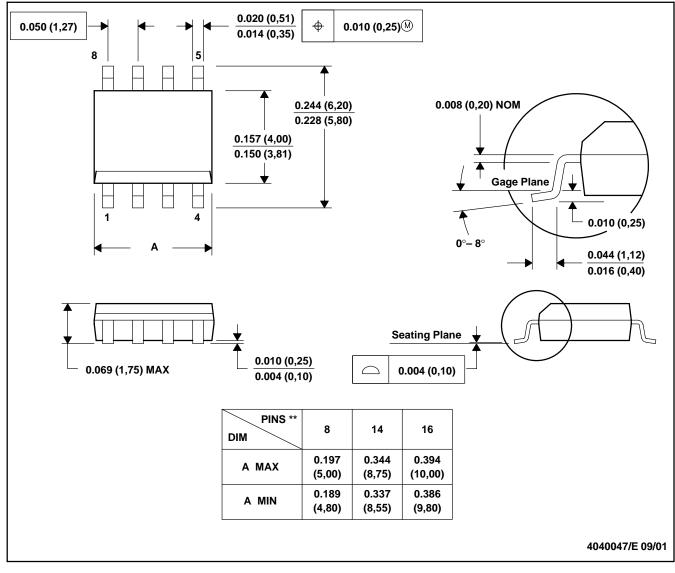


MECHANICAL DATA

MSOI002B - JANUARY 1995 - REVISED SEPTEMBER 2001

PLASTIC SMALL-OUTLINE PACKAGE

D (R-PDSO-G**) 8 PINS SHOWN



NOTES: A. All linear dimensions are in inches (millimeters).

- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion, not to exceed 0.006 (0,15).
- D. Falls within JEDEC MS-012



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